

## NOTICE OF REFERENCES CITED

APPLICANT(S)

Chen et al.

## U.S. PATENT DOCUMENTS

*	DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE
A	5 0 1 2 4 3 9	Apr. 30, 1991	Nash et al.	364	766	
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C	5 2 9 7 0 7 3	May. 23, 1994	Davidian	364	766	
D	5 0 9 7 4 3 5	Mar. 17, 1992	Takahashi	364	766	
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M								
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## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

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EXAMINER

Emmanuel Hoise

DATE

08/26/96

\* A copy of this reference is not being furnished with this office action.  
(See Manual of Patent Examining Procedure, section 707.05 (a).)